

NIKO-SEM

**P-Channel Logic Level Enhancement
Mode Field Effect Transistor**

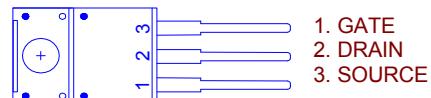
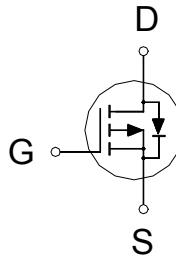
P1604ETF

TO-220F

Halogen-Free & Lead-Free

**PRODUCT SUMMARY**

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
-40V	16mΩ	-40A

**ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNITS
Drain-Source Voltage		V_{DS}	-40	V
Gate-Source Voltage		V_{GS}	±20	V
Continuous Drain Current	$T_C = 25^\circ\text{C}$	I_D	-40	A
	$T_C = 100^\circ\text{C}$		-25	
Pulsed Drain Current ¹		I_{DM}	-120	
Avalanche Current		I_{AS}	-40	
Avalanche Energy	$L = 0.1\text{mH}$	E_{AS}	78	
Power Dissipation	$T_C = 25^\circ\text{C}$	P_D	42	
	$T_C = 100^\circ\text{C}$		17	
Operating Junction & Storage Temperature Range		T_j, T_{stg}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$	3	60	°C / W
Junction-to-Ambient	$R_{\theta JA}$			

¹Pulse width limited by maximum junction temperature.

ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0\text{V}, I_D = -250\mu\text{A}$	-40			V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = -250\mu\text{A}$	-1.5	-2.2	-3	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0\text{V}, V_{GS} = \pm 20\text{V}$			±100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = -32\text{V}, V_{GS} = 0\text{V}$			1	μA
		$V_{DS} = -30\text{V}, V_{GS} = 0\text{V}, T_J = 125^\circ\text{C}$			10	
On-State Drain Current ¹	$I_{D(ON)}$	$V_{DS} = -5\text{V}, V_{GS} = -10\text{V}$	-120			A

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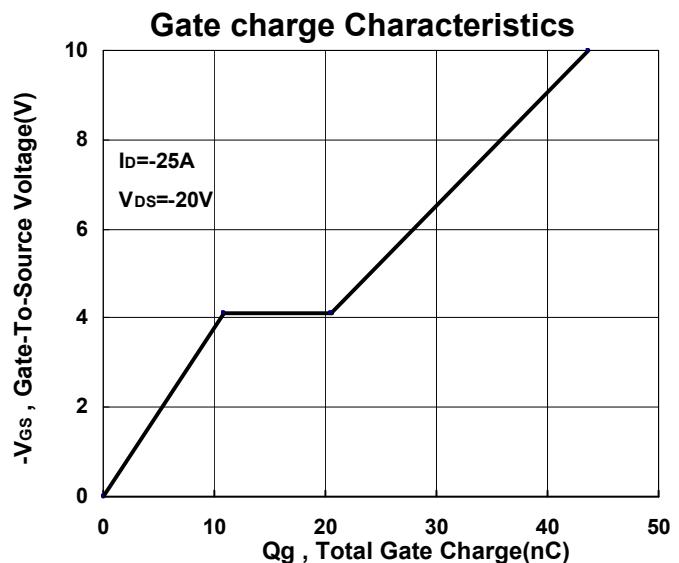
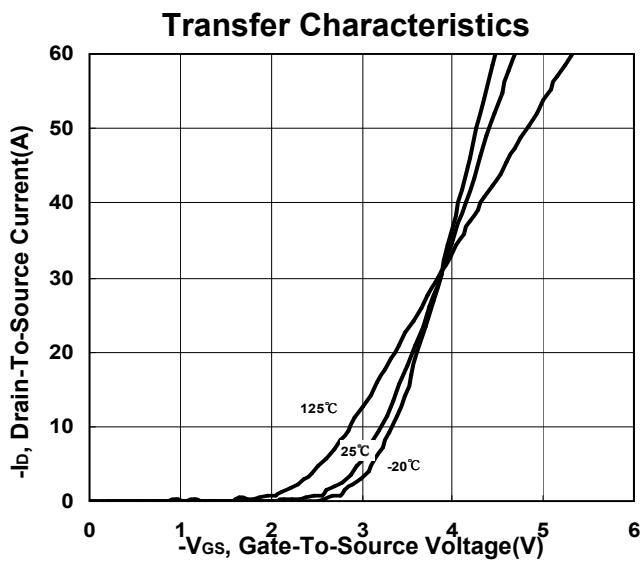
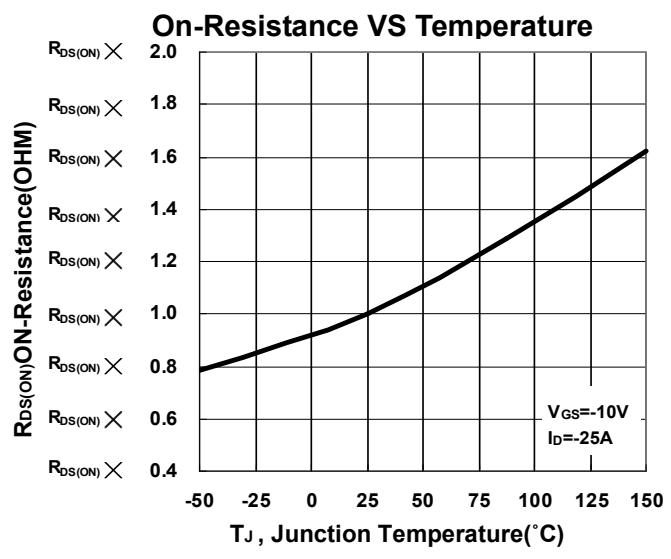
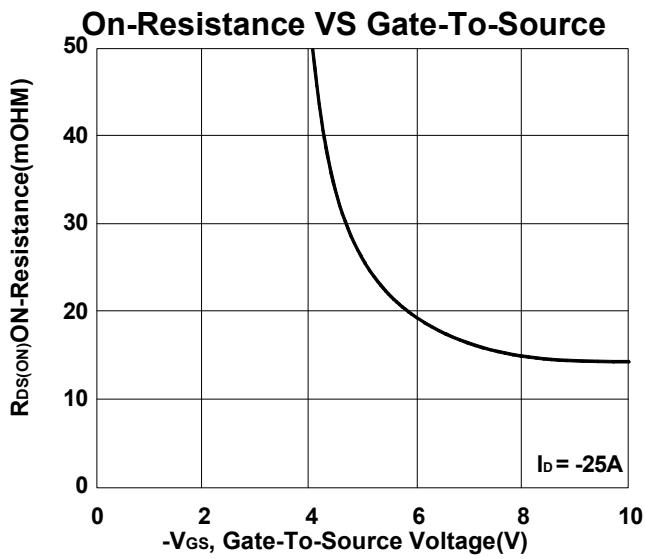
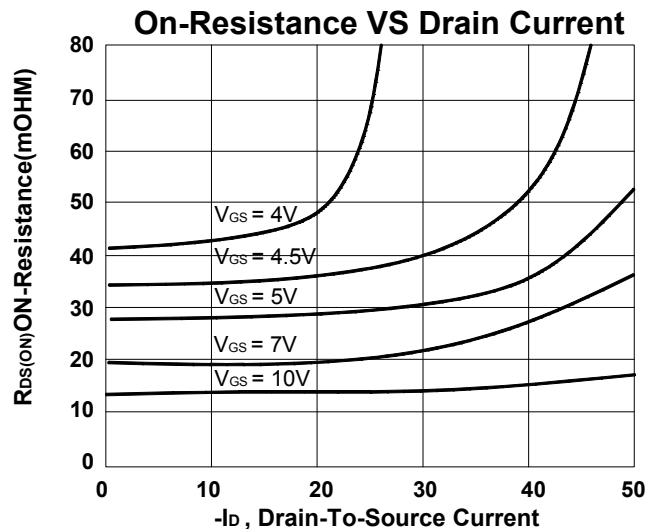
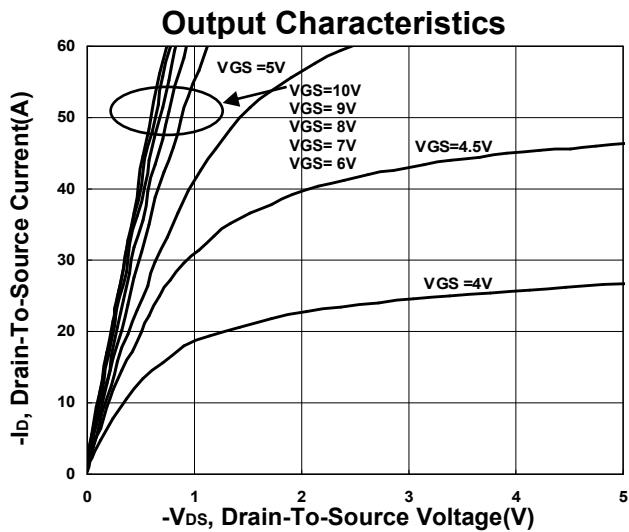
Drain-Source On-State Resistance ¹	$R_{DS(ON)}$	$V_{GS} = -7V, I_D = -15A$		16	20	$m\Omega$
		$V_{GS} = -10V, I_D = -25A$		13	16	
Forward Transconductance ¹	g_{fs}	$V_{DS} = -10V, I_D = -25A$		38		S
DYNAMIC						
Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = -20V, f = 1MHz$		2310		pF
Output Capacitance	C_{oss}			438		
Reverse Transfer Capacitance	C_{rss}			320		
Gate Resistance	R_g	$V_{GS} = 0V, V_{DS} = 0V, f = 1MHz$		4.3		Ω
Total Gate Charge ²	Q_g	$V_{DS} = 0.5V_{(BR)DSS}, V_{GS} = -10V, I_D = -25A$		45		nC
Gate-Source Charge ²	Q_{gs}			12		
Gate-Drain Charge ²	Q_{gd}			11		
Turn-On Delay Time ²	$t_{d(on)}$	$V_{DS} = -20V$ $I_D \approx -25A, V_{GS} = -10V, R_{GS} = 6\Omega$		15		nS
Rise Time ²	t_r			43		
Turn-Off Delay Time ²	$t_{d(off)}$			62		
Fall Time ²	t_f			50		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_J = 25^\circ C$)						
Continuous Current	I_S				-40	A
Forward Voltage ¹	V_{SD}	$I_F = -25A, V_{GS} = 0V$			1.3	V
Reverse Recovery Time	t_{rr}	$I_F = -25A, dI_F/dt = 100A / \mu S$		43		nS
Reverse Recovery Charge	Q_{rr}			31		nC

¹Pulse test : Pulse Width $\leq 300 \mu sec$, Duty Cycle $\leq 2\%$.²Independent of operating temperature.

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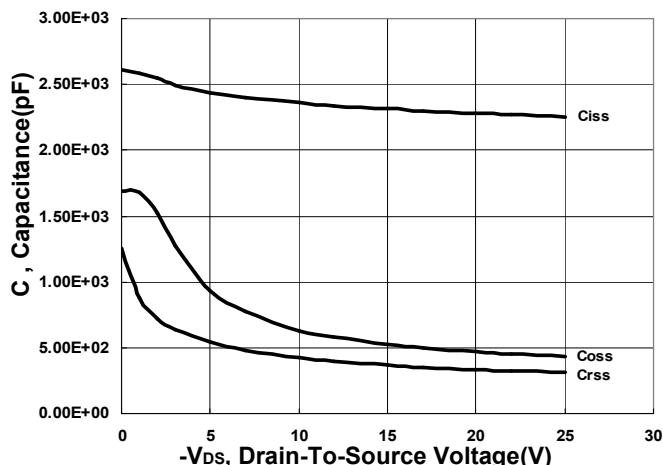
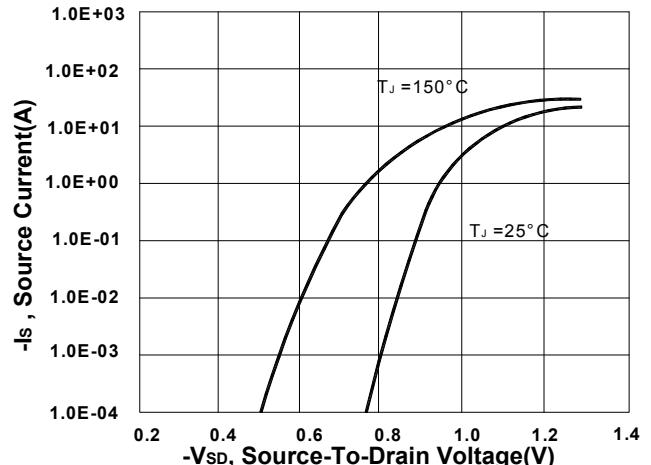
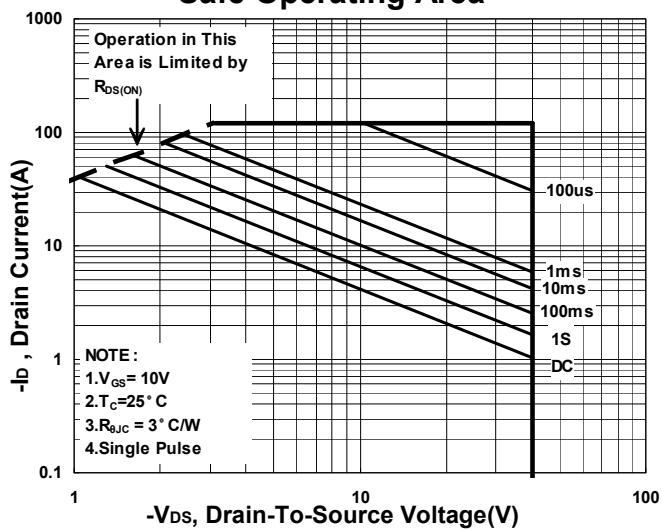
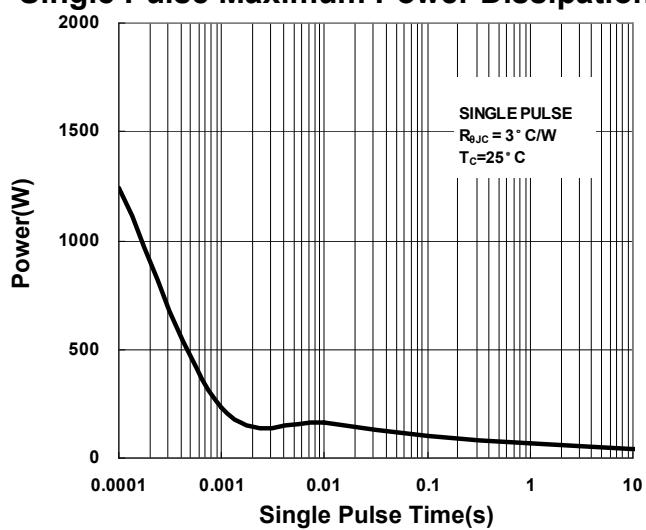
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Capacitance Characteristic**Body Diode Forward Voltage VS Source current****Safe Operating Area****Single Pulse Maximum Power Dissipation****Transient Thermal Response Curve**